



STW

**PATENT APPLICATION**

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re application of

Docket No: Q66584

Masayuki NAYA, et al.

Appln. No.: 10/053,585

Group Art Unit: 1641

Confirmation No.: 3648

Examiner: Christopher L. Chin

Filed: January 24, 2002

For: SURFACE PLASMON RESONANCE MEASURING CHIP AND METHOD OF  
MANUFACTURE THEREOF

**RESPONSE TO RESTRICTION REQUIREMENT**


Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450  
Sir:

In response to the Restriction Requirement, dated September 30, 2004, Applicants elect Group I, claims 1-12 for examination. This election is made without traverse.

Applicants reserve the right to file a Divisional Application directed to non-elected claim 13.

The USPTO is directed and authorized to charge all required fees, except for the Issue Fee and the Publication Fee, to Deposit Account No. 19-4880. Please also credit any overpayments to said Deposit Account.

Respectfully submitted,

  
Darryl Mexico

Registration No. 23,063

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WASHINGTON OFFICE

**23373**

CUSTOMER NUMBER

Date: October 29, 2004